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What is "Embedded - Microcontrollers"?

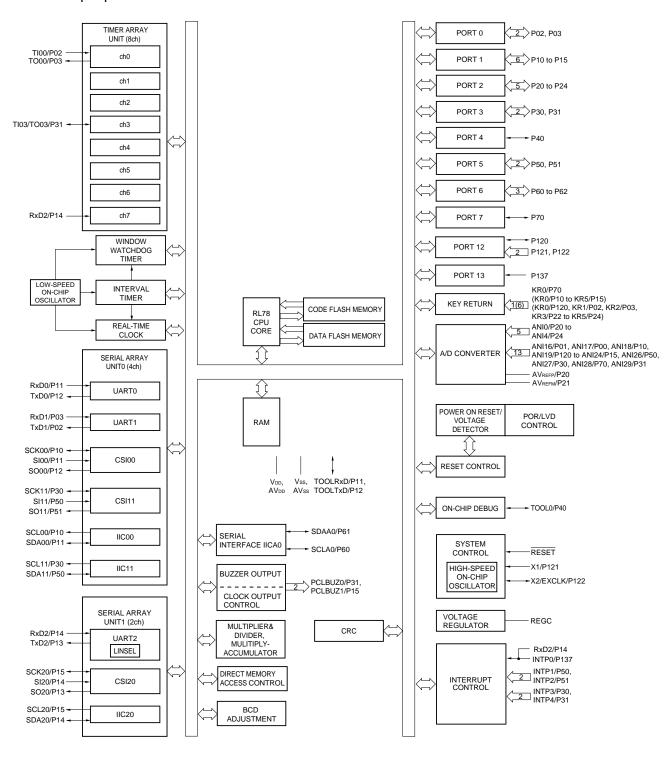
"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded - Microcontrollers</u>"

Details	
Product Status	Active
Core Processor	RL78
Core Size	16-Bit
Speed	32MHz
Connectivity	CSI, I ² C, LINbus, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	14
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 3.6V
Data Converters	A/D 13x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	25-WFLGA
Supplier Device Package	25-LGA (3x3)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f10e8cala-u0

RL78/G1A 1. OUTLINE

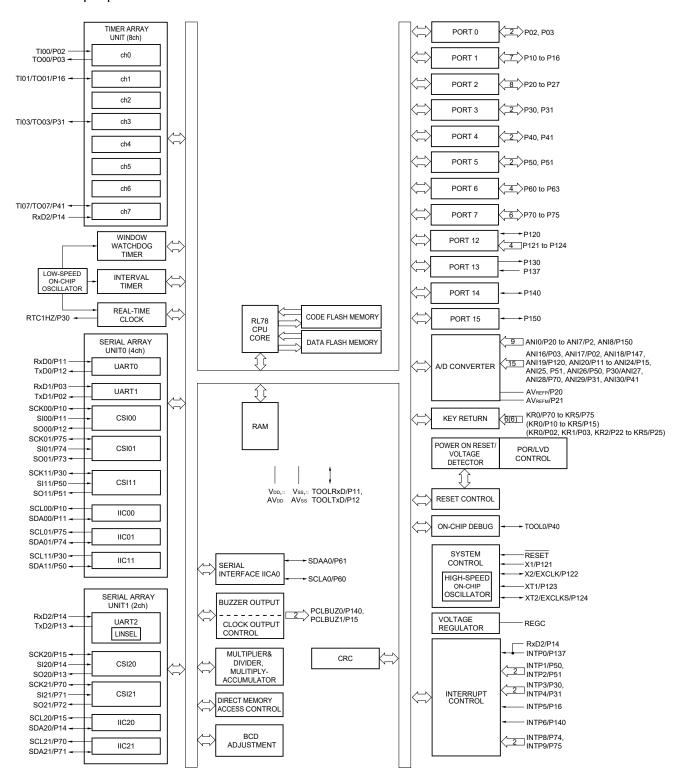
<R> 1.5.2 32-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

RL78/G1A 1. OUTLINE

<R> 1.5.3 48-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

RL78/G1A 1. OUTLINE

(2/2)

					(2/2)				
Ite	m	25-pin	32-pin	48-pin	64-pin				
		R5F10E8x	R5F10EBx	R5F10EGx	R5F10ELx				
Clock output/buzz	er output	1 • 2.44 kHz, 4.88 kHz, 9.7 2.5 MHz, 5 MHz, 10 M (Main system clock: fw		2 • 2.44 kHz, 4.88 kHz, 9.76 kHz, 1.25 MHz, 2.5 MHz, 5 MHz, 10 MHz (Main system clock: f _{Main} = 20 MHz operation) • 256 Hz, 512 Hz, 1.024 kHz, 2.048 kHz, 4.096 kHz, 8.192 kHz, 16.384 kHz, 32.768 kHz					
8/12-bit resolution	A/D converter	(Subsystem clock: fsuB = 32.768 kHz operation) 13 channels							
Serial interface		[25-pin products]	1 12 211211111212						
		 CSI: 1 channel/simplified I²C: 1 channel/UART: 1 channel CSI: 1 channel/simplified I²C: 1 channel/UART: 1 channel [32-pin products] CSI: 1 channel/simplified I²C: 1 channel/UART: 1 channel CSI: 1 channel/simplified I²C: 1 channel/UART: 1 channel CSI: 1 channel/simplified I²C: 1 channel/UART (UART supporting LIN-bus): 1 channel [48-pin products] CSI: 2 channels/simplified I²C: 2 channels/UART: 1 channel CSI: 1 channel/simplified I²C: 1 channel/UART: 1 channel CSI: 2 channels/simplified I²C: 2 channels/UART (UART supporting LIN-bus): 1 channel CSI: 2 channels/simplified I²C: 2 channels/UART (UART supporting LIN-bus): 1 channel [64-pin products] CSI: 2 channels/simplified I²C: 2 channels/UART: 1 channel CSI: 2 channels/simplified I²C: 2 channels/UART: 1 channel 							
	I ² C bus	1 channel	olified I ² C: 2 channels/UA 1 channel	1 channel	1 channel				
Multiplier and divider/multiply-ac	cumulator	 16 bits × 16 bits = 32 bits (Unsigned or signed) 32 bits ÷ 32 bits = 32 bits (Unsigned) 16 bits × 16 bits + 32 bits = 32 bits (Unsigned or signed) 							
DMA controller		2 channels							
Vectored interrupt	Internal	24	27	27	27				
sources	External	6	6	10	13				
Key interrupt		0 ch (4 ch) ^{Note 1}	1 ch (6 ch) ^{Note 1}	6 ch	10 ch				
Reset		 Reset by RESET pin Internal reset by watchdog timer Internal reset by power-on-reset Internal reset by voltage detector Internal reset by illegal instruction execution^{Note 2} Internal reset by RAM parity error Internal reset by illegal-memory access 							
Power-on-reset ci	rcuit	Power-on-reset: 1.51 V (TYP.) Power-down-reset: 1.50 V (TYP.)							
Voltage detector		 Rising edge: 1.67 V to 3.14 V (12 stages) Falling edge: 1.63 V to 3.06 V (12 stages) 							
On-chip debug fur	nction	Provided							
Power supply volta	age	V _{DD} = 1.6 to 3.6 V							
Operating ambien	t temperature	$T_A = -40 \text{ to } +85^{\circ}\text{C } (A: C)$	onsumer application), Ta	= -40 to +105°C (G: Indu	strial application)				

Notes 1. Can be used by the Peripheral I/O redirection register (PIOR).

2. The illegal instruction is generated when instruction code FFH is executed.
Reset by the illegal instruction execution not issued by emulation with the in-circuit emulator or on-chip debug emulator.

2.1 Absolute Maximum Ratings

Absolute Maximum Ratings ($T_A = 25^{\circ}C$) (1/2)

Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	V _{DD}		-0.5 to +6.5	V
	EV _{DD0}		-0.5 to +6.5	V
	AVDD		-0.5 to +4.6	V
	AVREFP		-0.3 to AV _{DD} +0.3 ^{Note 3}	V
	EVsso		-0.5 to +0.3	V
	AVss		-0.5 to +0.3	V
	AVREFM		-0.3 to AV _{DD} +0.3 ^{Note 3} and AV _{REFM} ≤ AV _{REFP}	V
REGC pin input voltage	Virego	REGC	-0.3 to +2.8 and -0.3 to V _{DD} +0.3 ^{Note 1}	V
Input voltage	VII	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P140, P141	-0.3 to EV _{DD0} +0.3 and -0.3 to V _{DD} +0.3 ^{Note 2}	V
	Vı2	P60 to P63 (N-ch open-drain)	-0.3 to +6.5	V
	Vı3	P121 to P124, P137, EXCLK, EXCLKS, RESET	-0.3 to V _{DD} +0.3 ^{Note 2}	V
	V _{I4}	P20 to P27, P150 to P154	-0.3 to AV _{DD} +0.3 ^{Note 2}	V
Output voltage	Vo ₁	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P63, P70 to P77, P120, P130, P140, P141	-0.3 to EV _{DD0} +0.3 ^{Note 2}	V
	V _{O2}	P20 to P27, P150 to P154	-0.3 to AV _{DD} +0.3 ^{Note 2}	V
Analog input voltage	Val1	ANI16 to ANI30	-0.3 to EV _{DD0} +0.3 and -0.3 to AV _{REF(+)} +0.3 ^{Notes 2, 4}	V
	V _{Al2}	ANI0 to ANI12	-0.3 to AV _{DD} +0.3 and -0.3 to AV _{REF(+)} +0.3 ^{Notes 2, 4}	V

- **Notes 1.** Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.
 - 2. Must be 6.5 V or lower.
 - 3. Must be 4.6 V or lower.
 - **4.** Do not exceed AV_{REF(+)} + 0.3 V in case of A/D conversion target pin.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

- **Remarks 1.** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.
 - **2.** AV_{REF(+)}: + side reference voltage of the A/D converter.
 - 3. Vss: Reference voltage

(3) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output) $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.6 \text{ V} \le \text{EV}_{DDO} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{V}_{SS} = \text{EV}_{SSO} = 0 \text{ V})$

Parameter	Symbol	Conditions	S	HS ^t	Note 1	LS ^N	lote 2	LV	lote 3	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkcy2	2.7 V ≤ EV _{DD0} ≤ 3.6 V	tkcy1 ≥ 4/fclk	125		500		1000		ns
		2.4 V ≤ EV _{DD0} ≤ 3.6 V	tkcy1 ≥ 4/fclk	250		500		1000		ns
		1.8 V ≤ EV _{DD0} ≤ 3.6 V	tkcy1 ≥ 4/fcLK	500		500		1000		ns
		$1.7~\text{V} \leq \text{EV}_{\text{DD0}} \leq 3.6~\text{V}$	tkcy1 ≥ 4/fclk	1000		1000		1000		ns
		1.6 V ≤ EV _{DD0} ≤ 3.6 V	tkcy1 ≥ 4/fclk	-		1000		1000		ns
SCKp high-/low-level width	t _{KH2} ,	2.7 V ≤ EV _{DD0} ≤ 3.6 V		tксү2/2 -18		tксү2/2 -50		tксү2/2 -50		ns
		2.4 V ≤ EV _{DD0} ≤ 3.6 V		tксү2/2 -38		tксү2/2 -50		tксү2/2 -50		ns
		1.8 V ≤ EV _{DD0} ≤ 3.6 V		tксү2/2 -50		tксү2/2 -50		tксү2/2 -50		ns
		1.7 V ≤ EV _{DD0} ≤ 3.6 V		tксү2/2 -100		tксү2/2 -100		tксү2/2 -100		ns
		1.6 V ≤ EV _{DD0} ≤ 3.6 V		_		tксү2/2 -100		tксү2/2 -100		ns
SIp setup time	tsık2	$2.7~\text{V} \leq \text{EV}_{\text{DD0}} \leq 3.6~\text{V}$		44		110		110		ns
(to SCKp↑) ^{Note 4}		$2.4~V \leq EV_{DD0} \leq 3.6~V$		75		110		110		ns
		1.8 V ≤ EV _{DD0} ≤ 3.6 V		110		110		110		ns
		1.7 V ≤ EV _{DD0} ≤ 3.6 V		220		220		220		ns
		1.6 V ≤ EV _{DD0} ≤ 3.6 V		_		220		220		ns
SIp hold time	t _{KSI2}	1.7 V ≤ EV _{DD} ≤ 3.6 V		19		19		19		ns
(from SCKp↑)Note 4		$1.6 \text{ V} \leq \text{EV}_{\text{DD}} \leq 3.6 \text{ V}$		_		19		19		ns
Delay time from SCKp↓	tkso2	$1.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 3.6 \text{ V}$	$C = 30 \text{ pF}^{\text{Note 6}}$		25		25		25	ns
to SOp outputNote 5		$1.6 \text{ V} \leq \text{EV}_{\text{DD}} \leq 3.6 \text{ V}$	$C = 30 pF^{Note 6}$		_		25		25	ns

Notes 1. HS is condition of HS (high-speed main) mode.

- 2. LS is condition of LS (low-speed main) mode.
- 3. LV is condition of LV (low-voltage main) mode.
- **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **5.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 6. C is the load capacitance of the SCKp and SOp output lines.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remark p: CSI number (p = 00, 01, 10, 11, 20, 21), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM and POM numbers (g = 0, 1)

- Notes 1. HS is condition of HS (high-speed main) mode.
 - 2. LS is condition of LS (low-speed main) mode.
 - 3. LV is condition of LV (low-voltage main) mode.
 - 4. Transfer rate in the SNOOZE mode: MAX. 1 Mbps
 - **5.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - **6.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 7. C is the load capacitance of the SOp output lines.

Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

- Remarks 1. p: CSI number (p = 00, 01, 10, 11, 20, 21), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM number (g = 0, 1)
 - 2. fmck: Serial array unit operation clock frequency

 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,

 n: Channel number (mn = 00 to 03, 10, 11))

(8) Communication at different potential (1.8V, 2.5 V) (CSI mode) (master mode, SCKp... internal clock output) (1/2)

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.8 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$

Parameter	Symbol	Conditions	Conditions			LSN	ote 2	LV ^N	ote 3	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
SCKp cycle time	tkcy1	$2.7 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 3.6 \text{ V},$ $2.3 \text{ V} \leq \text{V}_{\text{b}} \leq 2.7 \text{ V},$ $C_{\text{b}} = 30 \text{ pF}, \text{ R}_{\text{b}} = 2.7 \text{ k}\Omega$ $\text{tkcy1} \geq 4/\text{fclk}$		500		1150		1150		ns
		$\begin{split} 1.8 \ V &\leq EV_{DD0} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 4}}, \\ C_b &= 30 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$	tkcy1 ≥ 4/fclk	1150		1150		1150		ns
SCKp high-level width	tкн1	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}, 2.3 \text{ V} \le C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	$\leq V_b \leq 2.7 V$,	tксу1/2 — 170		tксү1/2 — 170		tксү1/2 — 170		ns
		$\begin{array}{l} 1.8 \text{ V} \leq \text{EV}_{\text{DD0}} < 3.3 \text{ V}, \ 1.6 \text{ V} \leq \\ 4, \\ C_b = 30 \text{ pF}, \ R_b = 5.5 \text{ k}\Omega \end{array}$	1.8 V \leq EV _{DD0} $<$ 3.3 V, 1.6 V \leq V _b \leq 2.0 V ^{Note} s, C _b = 30 pF, R _b = 5.5 kΩ			tkcy1/2 – 458		tксү1/2 – 458		ns
SCKp low-level width	t _{KL1}	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}, 2.3 \text{ V} \le C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	tксу1/2 — 18		tксү1/2 — 50		tксү1/2 — 50		ns	
		$1.8 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V}, 1.6 \text{ V} \le 4$, $C_b = 30 \text{ pF}, R_b = 5.5 \text{ k}\Omega$	$\leq V_b \leq 2.0 \text{ V}^{\text{Note}}$	tксу1/2 — 50		tkcy1/2 – 50		tксү1/2 — 50		ns

- Notes 1. HS is condition of HS (high-speed main) mode.
 - 2. LS is condition of LS (low-speed main) mode.
 - 3. LV is condition of LV (low-voltage main) mode.
 - **4.** Use it with $EV_{DD0} \ge V_b$.

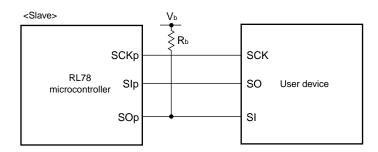
Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VH and VIL, see the DC characteristics with TTL input buffer selected.

- **Remarks 1.** R_b[Ω]: Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage
 - 2. p: CSI number (p = 00, 10, 20), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1)
 - **3.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

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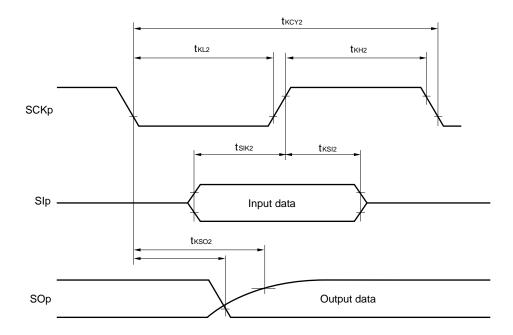
Nov 30, 2016

CSI mode connection diagram (during communication at different potential)

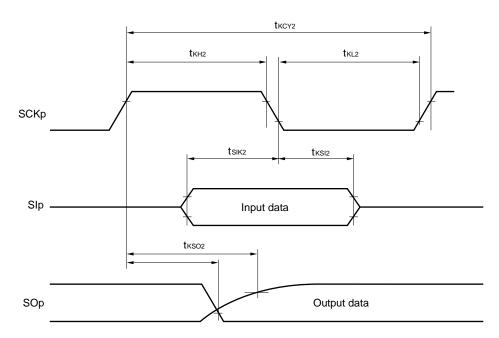


- **Remarks 1.** $R_b[\Omega]$: Communication line (SOp) pull-up resistance, $C_b[F]$: Communication line (SOp) load capacitance, $V_b[V]$: Communication line voltage
 - 2. p: CSI number (p = 00, 10, 20), m: Unit number (m = 0, 1), n: Channel number (n = 00, 02, 10), g: PIM and POM number (g = 0, 1)
 - 3. fmck: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 02, 10))
 - **4.** CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



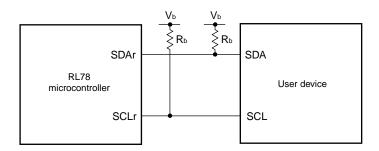
CSI mode serial transfer timing (slave mode) (during communication at different potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



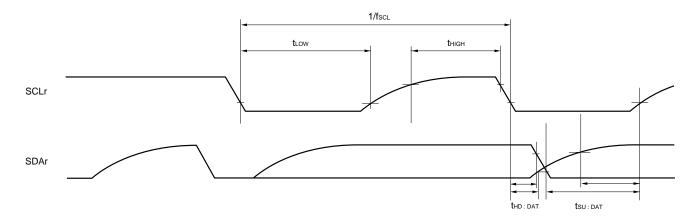
Remarks 1. p: CSI number (p = 00, 10, 20), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1)

2. CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

Simplified I²C mode connection diagram (during communication at different potential)

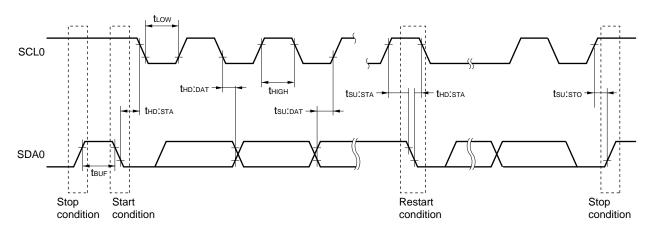


Simplified I²C mode serial transfer timing (during communication at different potential)



- **Remarks 1.** Rb[Ω]: Communication line (SDAr, SCLr) pull-up resistance, Cb[F]: Communication line (SDAr, SCLr) load capacitance, Vb[V]: Communication line voltage
 - 2. r: IIC number (r = 00, 10, 20), g: PIM, POM number (g = 0, 1)
 - 3. fmck: Serial array unit operation clock frequency
 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,
 n: Channel number (mn = 00, 02, 10)
 - **4.** IIC01, IIC11, and IIC21 cannot communicate at different potential. Use IIC00, IIC10, or IIC20 for communication at different potential.

IICA serial transfer timing



<R> (2) When reference voltage (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target for conversion: ANI2 to ANI12

(TA = -40 to +85°C, 1.6 V \leq AVREFP \leq AVDD \leq VDD \leq 3.6 V, Vss = 0 V, AVss = 0 V, Reference voltage (+) = AVREFP, Reference voltage (-) = AVREFM = 0 V)

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Resolution	Res		$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	8		12	bit
			$1.8 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	8		10 ^{Note 1}	
			$1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$		8 ^{Note 2}		
Overall error ^{Note 3}	AINL	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±6.0	LSB
		10-bit resolution	$1.8 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±5.0	
		8-bit resolution	$1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±2.5	
Conversion time	tconv	ADTYP = 0, 12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	3.375			μs
		ADTYP = 0, 10-bit resolution ^{Note 1}	1.8 V ≤ AVREFP ≤ AVDD ≤ 3.6 V	6.75			
		ADTYP = 0, 8-bit resolution ^{Note 2}	1.6 V ≤ AVREFP ≤ AVDD ≤ 3.6 V	13.5			
		ADTYP = 1,	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	2.5625			
		8-bit resolution	$1.8 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	5.125			
			$1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	10.25			
Zero-scale error ^{Note 3}	Ezs	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±4.5	LSB
		10-bit resolution	$1.8 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±4.5	
		8-bit resolution	$1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±2.0	
Full-scale errorNote 3	Ers	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±4.5	LSB
		10-bit resolution	$1.8~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$			±4.5	
		8-bit resolution	$1.6~V \le AV_{REFP} \le AV_{DD} \le 3.6~V$			±2.0	
Integral linearity error Note 3	ILE	12-bit resolution	$2.4~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$			±2.0	LSB
		10-bit resolution	$1.8~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$			±1.5	
		8-bit resolution	$1.6~V \le AV_{REFP} \le AV_{DD} \le 3.6~V$			±1.0	
Differential linearity errorNote 3	DLE	12-bit resolution	$2.4~V \leq AV_{REFP} \leq AV_{DD} \leq 3.6~V$			±1.5	LSB
		10-bit resolution	$1.8 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±1.5	
		8-bit resolution	$1.6 \text{ V} \le \text{AV}_{\text{REFP}} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±1.0	
Analog input voltage	Vain			0		AVREFP	٧

- Notes 1. Cannot be used for lower 2 bit of ADCR register
 - 2. Cannot be used for lower 4 bit of ADCR register
 - 3. Excludes quantization error (±1/2 LSB).

3. ELECTRICAL SPECIFICATIONS (G: INDUSTRIAL APPLICATIONS $T_A = -40 \text{ to } +105^{\circ}\text{C}$)

This chapter describes the following electrical specifications.

Target products G: Industrial applications T_A = -40 to +105°C
R5F10EBAGNA, R5F10EBCGNA, R5F10EBDGNA, R5F10EBEGNA
R5F10EGAGFB, R5F10EGCGFB, R5F10EGDGFB, R5F10EGEGFB
R5F10EGAGNA, R5F10EGCGNA, R5F10EGDGNA, R5F10EGEGNA
R5F10ELCGFB, R5F10ELDGFB, R5F10ELEGFB

- Cautions 1. The RL78/G1A has an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
 - 2. With products not provided with an EV_{DD0} or EVss₀ pin, replace EV_{DD0} with V_{DD}, or replace EVss₀ with Vss.
 - 3. Please contact Renesas Electronics sales office for derating of operation under T_A = +85°C to +105°C. Derating is the systematic reduction of load for the sake of improved reliability.

Remark When RL78/G1A is used in the range of $T_A = -40$ to +85°C, see 2. **ELECTRICAL SPECIFICATIONS** ($T_A = -40$ to +85°C).



<R> (TA = -40 to +105°C, 2.4 V ≤ AVDD ≤ VDD ≤ 3.6 V, 2.4 V ≤ EVDD0 ≤ VDD ≤ 3.6 V, Vss = EVss0 = 0 V) (2/5)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, low ^{Note 1}	lo _{L1}	Per pin for P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P130, P140, P141				8.5 ^{Note 2}	mA
		Per pin for P60 to P63				15.0 ^{Note 2}	mA
		Total of P00 to P04, P40 to P43, P120, P130, P140, P141	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V}$			15.0	mA
		P130, P140, P141 (When duty ≤ 70% ^{Note 3})	2.4 V ≤ EV _{DD0} < 2.7 V			9.0	mA
		11, 11,	$2.7~V \le EV_{DD0} \le 3.6~V$			35.0	mA
		P31, P50, P51, P60 to P63, P70 to P77 (When duty ≤ 70% ^{Note 3})	2.4 V ≤ EV _{DD0} < 2.7 V			20.0	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})				50.0	mA
	lol2	Per pin for P20 to P27, P150 to P154				0.4 ^{Note 2}	mA
		Total of all pins (When duty $\leq 70\%^{\text{Note 3}}$)	$2.4 \text{ V} \le \text{AV}_{DD} \le 3.6 \text{ V}$			5.2	mA

- **Notes 1**. Value of current at which the device operation is guaranteed even if the current flows from an output pin to the EVsso and Vss pin.
 - 2. However, do not exceed the total current value.
 - 3. Specification under conditions where the duty factor ≤ 70%.
 The output current value that has changed to the dury factor > 70% the duty ratio can can be calculated with the following expression (when changing the duty factor from 70% to n%).
 - Total output current of pins = (IoL × 0.7)/(n × 0.01)
 <Example> Where n = 80% and IoL = 10.0 mA
 Total output current of pins = (10.0 × 0.7)/(80 × 0.01) ≅ 8.7 mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

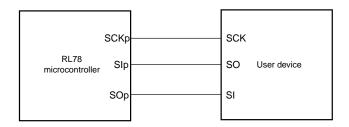
Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le \text{EV}_{DD0} \le \text{V}_{DD} \le 3.6 \text{ V}, \text{Vss} = \text{EV}_{SS0} = 0 \text{ V})$ (2/3)

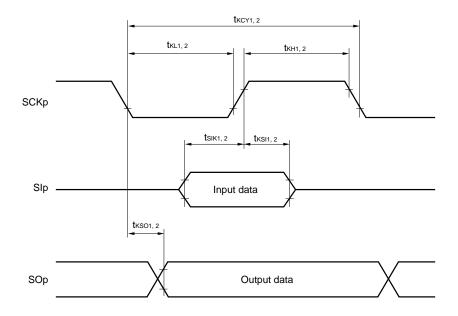
Parameter	Symbol	, • <u>-</u> -		V, V ss = EV sso = $0 VConditions$		MIN.	TYP.	MAX.	(2/3) Unit
Supply	I _{DD2} Note 2	HALT	HS (high-speed	f _{IH} = 32 MHz ^{Note 4}	V _{DD} = 3.0 V		0.54	2.90	mA
current ^{Note 1}		mode	main) mode ^{Note 7}	f _{IH} = 24 MHz ^{Note 4}	V _{DD} = 3.0 V		0.44	2.30	mA
				f _{IH} = 16 MHz ^{Note 4}	V _{DD} = 3.0 V		0.40	1.70	mA
			HS (high-speed	speed f _{MX} = 20 MHz ^{Note 3} ,	Square wave input		0.28	1.90	mA
			main) mode ^{Note 7}	$V_{DD} = 3.0 \text{ V}$	Resonator connection		0.45	2.00	
				f _{MX} = 10 MHz ^{Note 3} ,	Square wave input		0.19	1.02	mA
				$V_{DD} = 3.0 \text{ V}$	Resonator connection		0.26	1.10	
			Subsystem clock	f _{SUB} = 32.768 kHz ^{Note 5}	Square wave input		0.25	0.57	μΑ
			mode	T _A = -40°C	Resonator connection		0.44	0.76	
				f _{SUB} = 32.768 kHz ^{Note 5}	Square wave input		0.30	0.57	μΑ
				T _A = +25°C	Resonator connection		0.49	0.76	
			fsub = 32.768 kHz ^{Note 5}	Square wave input		0.38	1.17	μΑ	
				T _A = +50°C f _{SUB} = 32.768 kHz ^{Note 5}	Resonator connection		0.57	1.36	
					Square wave input		0.52	1.97	μΑ
				T _A = +70°C f _{SUB} = 32.768 kHz ^{Note 5}	Resonator connection		0.71	2.16	
					Square wave input		0.97	3.37	μΑ
				T _A = +85°C	Resonator connection		1.16	3.56	
				f _{SUB} = 32.768 kHz ^{Note 5} T _A = +105°C	Square wave input		3.01	15.37	μΑ
				1A - +105 C	Resonator connection		3.20	15.56	
	I _{DD3} Note 6	STOP	T _A = -40°C				0.16	0.50	μΑ
		mode ^{Note 8}	T _A = +25°C				0.23	0.50	
		T _A = +50°C				0.34	1.10		
			T _A = +70°C				0.46	1.90]
			T _A = +85°C				0.75	3.30	
			T _A = +105°C				2.94	15.30	

(Notes and Remarks are listed on the next page.)

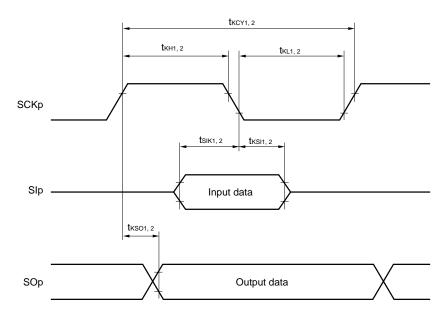
CSI mode connection diagram (during communication at same potential)



CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Remarks 1. p: CSI number (p = 00, 01, 10, 11, 20, 21)

2. m: Unit number, n: Channel number (mn = 00 to 03, 10, 11)

<R>

(5) Communication at different potential (1.8 V, 2.5 V) (UART mode) (dedicated baud rate generator output) (1/2) (T_A = −40 to +105°C, 2.4 V ≤ EV_{DD0} ≤ V_{DD} ≤ 3.6 V, V_{SS} = EV_{SS0} = 0 V)

Parameter	Symbol		Condition	MIN.	TYP.	MAX.	Unit	
Transfer rate ^{Note 1}		Reception	$2.7 \text{ V} \le \text{EV}_{\text{DD0}} \le 3.6 \text{ V},$				fмск/12	bps
			$2.3~V \leq V_b \leq 2.7~V$	Theoretical value of the maximum transfer rate fclk = 32 MHz, fMck = fclk			2.6	Mbps
			$2.4 \text{ V} \le \text{EV}_{\text{DD0}} < 3.3 \text{ V},$				fмск/12	bps
			$1.6~V \leq V_b \leq 2.0~V$	Theoretical value of the maximum transfer rate fclk = 32 MHz, fmck = fclk			2.6 ^{Note 2}	Mbps

- Notes 1. Transfer rate in the SNOOZE mode is 4800 bps.
 - 2. The following conditions are required for low-voltage interface when $EV_{DD0} < V_{DD}$.

 $2.4 \text{ V} \leq \text{EV}_{\text{DD0}} \leq 2.7 \text{ V}$: MAX. 1.3 Mbps

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance (When 25- to 48-pin products)/EVDD tolerance (When 64-pin products)) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VH and VL, see the DC characteristics with TTL input buffer selected.

Remarks 1. V_b[V]: Communication line voltage

- 2. q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)
- 3. fmck: Serial array unit operation clock frequency
 (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,

n: Channel number (mn = 00 to 03, 10, 11)



<R> (2) When reference voltage (+) = AV_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = AV_{SS} (ADREFM = 0), target for conversion: ANI0 to ANI12

(TA = -40 to +105°C, 2.4 V \leq AVDD \leq VDD \leq 3.6 V, Vss = 0 V, AVss = 0 V, Reference voltage (+) = AVDD, Reference voltage (-) = AVss = 0 V)

Parameter	Symbol	(Conditions	MIN.	TYP.	MAX.	Unit
Resolution	Res		$2.4 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$	8		12	bit
Overall error ^{Note}	AINL	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±7.5	LSB
Conversion time	tconv	ADTYP = 0, 12-bit resolution	2.4 V ≤ AV _{DD} ≤ 3.6 V	3.375			μs
Zero-scale error ^{Note}	Ezs	12-bit resolution	$2.4 \text{ V} \le \text{AV}_{\text{DD}} \le 3.6 \text{ V}$			±6.0	LSB
Full-scale error ^{Note}	Ers	12-bit resolution	2.4 V ≤ AV _{DD} ≤ 3.6 V			±6.0	LSB
Integral linearity error Note	ILE	12-bit resolution	$2.4 \text{ V} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±3.0	LSB
Differential linearity error Note	DLE	12-bit resolution	$2.4 \text{ V} \leq \text{AV}_{\text{DD}} \leq 3.6 \text{ V}$			±2.0	LSB
Analog input voltage	Vain			0		AV _{DD}	٧

Note Excludes quantization error (±1/2 LSB).

3.6.4 LVD circuit characteristics

LVD Detection Voltage of Reset Mode and Interrupt Mode

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, V_{PDR} \le V_{DD} \le 3.6 \text{ V}, V_{SS} = 0 \text{ V})$

	Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection	Supply voltage level	V _{LVD2}	Power supply rise time	3.01	3.13	3.25	V
voltage			Power supply fall time	2.94	3.06	3.18	٧
		V _{LVD3}	Power supply rise time	2.90	3.02	3.14	V
			Power supply fall time	2.85	2.96	3.07	٧
		V _{LVD4}	Power supply rise time	2.81	2.92	3.03	V
			Power supply fall time	2.75	2.86	2.97	V
		V _{LVD5}	Power supply rise time	2.70	2.81	2.92	V
			Power supply fall time	2.64	2.75	2.86	V
		V _{LVD6}	Power supply rise time	2.61	2.71	2.81	V
			Power supply fall time	2.55	2.65	2.75	V
		V _{LVD7}	Power supply rise time	2.51	2.61	2.71	V
			Power supply fall time	2.45	2.55	2.65	V
Minimum pu	lse width	t _{LW}		300			μs
Detection de	elay time					300	μs

Remark $V_{LVD(n-1)} > V_{LVDn}$: n = 3 to 7

LVD Detection Voltage of Interrupt & Reset Mode

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, V_{PDR} \le V_{DD} \le 3.6 \text{ V}, V_{SS} = 0 \text{ V})$

Parameter	Symbol		Cond	litions	MIN.	TYP.	MAX.	Unit
Interrupt & reset	V _{LVD5}	VPOC	2, VPOC1, VPOC0 = 0), 1, 1, falling reset voltage	2.64	2.75	2.86	V
mode	V _{LVD4}		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.81	2.92	3.03	V
				Falling interrupt voltage	2.75	2.86	2.97	V
	V _{LVD3}		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.90	3.02	3.14	V
				Falling interrupt voltage	2.85	2.96	3.07	V

Caution Set the detection voltage (VLVD) to be within the operating voltage range. The operating voltage range depends on the setting of the user option byte (000C2H/010C2H). The following shows the operating voltage range.

HS (high-speed main) mode: V_{DD} = 2.7 to 3.6 V@1 MHz to 32 MHz V_{DD} = 2.4 to 3.6 V@1 MHz to 16 MHz

3.6.5 Supply voltage rise slope characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Supply voltage rise	SV _{DD}				54	V/ms

Caution Be sure to maintain the internal reset state until V_{DD} reaches the operating voltage range specified in 3.4 AC Characteristics, by using the LVD circuit or external reset pin.

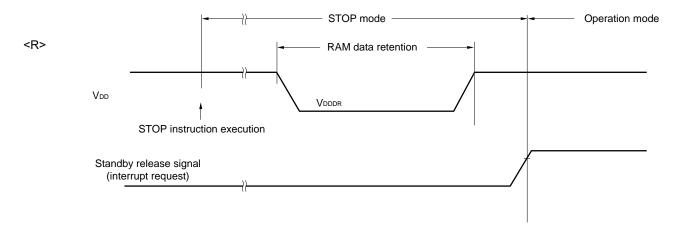


<R> 3.7 RAM Data Retention Characteristics

$< R > (T_A = -40 \text{ to } +105^{\circ}C, V_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.44 ^{Note}		3.6	V

Note This depends on the POR detection voltage. For a falling voltage, data in RAM are retained until the voltage reaches the level that triggers a POR reset but not once it reaches the level at which a POR reset is generated.



3.8 Flash Memory Programming Characteristics

 $(T_A = -40 \text{ to } +105^{\circ}\text{C}, 2.4 \text{ V} \le V_{DD} \le 3.6 \text{ V}, \text{Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
CPU/peripheral hardware clock frequency	fclk	$2.4 \text{ V} \le \text{V}_{DD} \le 3.6 \text{ V}$	1		32	MHz
Number of code flash rewrites ^{Notes 1, 2, 3}	Cerwr	Retained for 20 years TA = 85°C	1,000			Times
Number of data flash rewrites ^{Notes 1, 2, 3}		Retained for 1 years TA = 25°C		1,000,000		
		Retained for 5 years TA = 85°C	100,000			
		Retained for 20 years T _A = 85°C	10,000			

Notes 1. 1 erase + 1 write after the erase is regarded as 1 rewrite.

The retaining years are until next rewrite after the rewrite.

- 2. When using flash memory programmer and Renesas Electronics self programming library
- **3.** These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.
- 4. This temperature is the average value at which data are retained.

<R>